

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/767,724	OGAWA, HIDEHIKO	
		Examiner	Art Unit	
		Thomas D. Lee	2624	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,710,894	03-2004	Ogawa, Hidehiko	358/1.15
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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